



Researchers217Post docs13PhD students20250



MM area FCS – Physics & Chemistry of Surfaces and Interfaces MIS – Microsystems

IT area SRA – Automated Reasoning Sytems SSI – Interactive Sensory Systems TCC – Cognitive and Communication Technologies



MIS Microsystems

Head of Department: Mario Zen



The department designs and realises silicon microsystems, especially:

- silicon particle detectors;
- sensors for bio-medical and environmental applications;
- micro-electro-mechanic systems (MEMS) for industrial and consumer applications;
- electro-optic microsystems for vision and nondestructive measurements.



MEMS Technological fabrication modules



Silicon anisotropic etching with TMAH solution

Lithography with thick film of photoresist

Low temperature Wafer Bonding

Gold Electrodeposition

28KU X38,888



Clean Room

Fabrication: the Lab. covers an area of 500 sqm (250 of which are in class 10)

- Furnaces 11 horizontal furnaces (diffusion,LPCVD depositions, Si3N4, Polysilicon, TEOS, BPSG and LTO)
- Implanter "Varian E 220 medium current"
- Lithographic Sector : Mask Aligner A "Karl Suss MA 150 BSA" and Resist processing systems "SVG 8600" and "EVG 150".
- Etching Sector: Wet etching and Dry etching (Aluminium, Silicon dioxide Silicon nitride, Polysilicon etching)
- Metalization: Varian 3180 sputtering and Ulvac EBX-16C evaporator
- Dicing Disco DAD 2H-6T

Testing

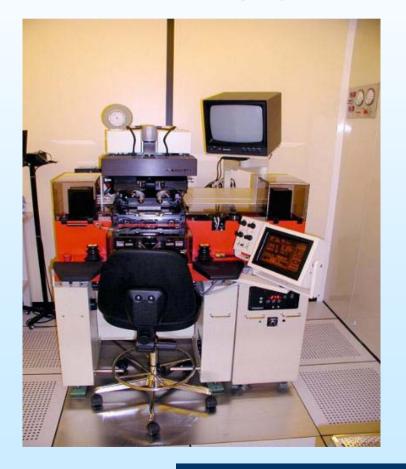
- HP 4062UX + EG2001CX custom modified for double-side wafer
- Karl Suess PM8 custom modified for double-side wafer testing



Lithographic Sector

Mask Aligner A "Karl Suss MA 150 BSA"

Resist processing systems "SVG 8600" and "EVG 150".







Etching Sector

Dry etching Aluminium, SiO_2 , Si_3N_4 and Poly







Metalization

Varian 3180 sputtering

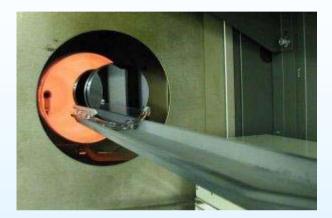


Ulvac EBX-16C evaporator









Furnaces 11 horizontal furnaces

diffusion, LPCVD depositions, Si3N4, Polysilicon, TEOS, BPSG and LTO





Ion Implanter

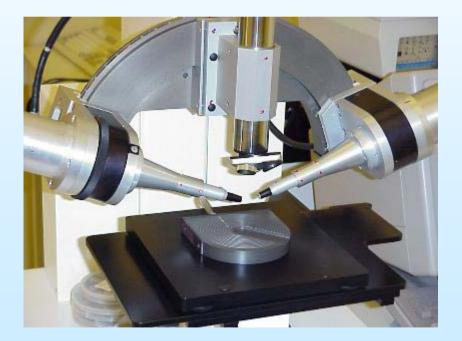
Varian E 220 medium current





Inspection Sector

- Olympus MX50 microscope
- Leitz MPV-SP Interferometer for thickness control.
- 4 point Napson RT8-8 for resistivity control.
- Plasmos SD 2300 Ellipsometer for refraction index control







Packaging Sector

Ultrasonic Gold Ball Bonder (K&S 4124).

Disco DAD 2H-6T







testing

Automatic wafer-level tester

cassette-to-cassette, double-side testing, automatic sorting & inking, HP 4062UX + EG2001CX - custom modified for double-side wafer testing

<u>Manual Probe Station</u> Karl Suess PM8

Electro-optical test system





New Equipments

Now in clean room

- PECVD STS for nitride and oxide deposition
- Tegal 6510 dry etch system for metal and poly&nitride

Plan for the next tree years

- Stepper
- wafer bonder
- dry etch system for metal
- deep RIE
- Boron deposition from solid source